

Report No.: SH2201260098

Version : A

## 闩锁试验报告

Latch up TEST REPORT

委托公司 : 武汉力源半导体有限公司

Company

公司地址 : 上海长宁区天山西路 567 号神州智慧大厦 3 楼

Address

产品名称 : <u>CW32L031</u>

Sample name

委托日期 : 2022 年 1 月 24 日

Date Received

完成日期 : 2022 年 1 月 17 日

Date Tested

#### 实验室认证体系 (TESTING LABORATORY IS APPROVAL BY):

证书编号: IECQ-L DEKRA 17.0004-01

IECQ Certificate of Approval No.: IECQ-L DEKRA 17.0004-01 For Independent

#### 实验室证明事项(WE HEREBY CERTIFY THAT):

对于本报告所载之测试项目及结果,实验室保证由训练合格之专业技术人员负责执行,并忠 实及完整将各项试验结果记录于报告内。

The test(s) shown in the attachment were conducted according to the indicating procedures. We assume full responsibility for the accuracy and completeness of these tests and vouch for the qualifications of all personnel performing them.

|                          | 名称 (Name)         | 签名 (Signature) | 日期 (Date)       |
|--------------------------|-------------------|----------------|-----------------|
| 检测员<br>Inspector         | 潘祥仁<br>Peter Pan  | 潘祥仁            | 2022年2月17号      |
| 报告审核人<br>Report reviewer | 陈清珑<br>Larry Chen | <b>渡清</b> 鸐    | 2022 年 2 月 17 号 |
| 报告批准人<br>Approver        | 李鹏云<br>Smile Li   | 李鹏云            | 2022 年 2 月 17 号 |

## 备注 (NOTE):

1. 本报告内容以任何方式翻印或复印部份者无效。
This report will be invalid if reproduced in part or altered in any way.

2. 本报告仅对检送样品负责,且分离使用无效。

This report refers only to the specimen(s) submitted to test, and is invalid if used otherwise

3. 本报告需加盖本公司印鉴及签名始生效。

This report is ONLY valid with the examination seal and signature of this institute.

4. 样品保存自报告签发日起30天。

The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant



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1. 讯息 (INFORMATION)

#### 1.1 案件讯息 (CASE INFORMATION)

| 试验样品        | 批次号     | 封装      | 数量       |
|-------------|---------|---------|----------|
| Test Sample | LOT NO. | Package | Quantity |
| CW32L031    | NA      | LQFP48  | 3 pcs    |

### 1.2 试验设备说明 (DESCRIPTION OF TEST EQUIPMENT)

| 项目    | 设备/编号         | 型号                       | 校准有效期                |
|-------|---------------|--------------------------|----------------------|
| Items | Equipment/No. | Model                    | Calibration validity |
| 1     | 1409189       | KEYTEK ZAPMASTER MK2 768 | 2022年03月23日          |

### 1.3 环境条件 (AMBIENCE CONDITION)

| 标准要求温度<br>Required<br>temperature         | 25,⁵ ℃     | 实际温度<br>Actual temperature | 23.3~23.8℃   |
|---|------------|----------------------------|--------------|
| 标准要求相对湿度<br>Required relative<br>humidity | 55± 10 %RH | 实际湿度<br>Actual humidity    | 51.4~51.9%RH |

#### 1.4 参考文件 (REFERENCE DOCUMENT)

| 项目    | 依据标准                              |
|-------|-----------------------------------|
| Items | Standards                         |
| 1     | JESD STANDARD NO.78F JANUARY 2022 |

#### 1.5 测试要求(TEST REQUIREMENT)

TRIGGER CURRENT  $: 300mA(\pm),400mA(\pm)$ 

**V SUPPLY OVER** : 5.25V~8.25V,STEP:1.0V (+) **VOLTAGE TEST** 

**PULSE DURATION** : 10 ms

TEST TEMPERATURE : ROOM TEMPERATURE

SAMPLE QUANTITY : 3 pcs

: If absolute Inom is < 25 mA, then absolute Inom + 10mA is used; Or **FAILURE CRITERIA** 

If absolute Inom is > 25 mA, then > 1.4X absolute Inom is used;

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电话(TeI): 86-21-61910691, 传真(Fax): 86-21-64069790

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## 2 试验结果 (TEST RESULTS)

## 2.1 结果汇整 (SUMMARY)

| Trigger Mode        | Test Pin | Sample<br>Quantity | Tested Result | V or I<br>Limits | FT Testing<br>Pass Volts |  |
|---------------------|----------|--------------------|---------------|------------------|--------------------------|--|
|                     |          |                    |               |                  |                          | Temperature Classification:                            |
|                     |          |                    |               |                  |                          | CLASS I  |
|                     | 105 5) / |                    | 5400 400 4    | 0.0517           |                          | For Latch-up test at room temperature                  |
| I Trigger (+)       | IO5.5V   |                    | PASS +400mA   | +8.25V           |                          | Class I A :  |
|                     |          |                    |               |                  |                          | Positive I-Test : ≧ 100mA                              |
|                     |          |                    |               |                  |                          | Negative I-Test : ≧ 100mA                              |
|                     |          |                    |               |                  |                          | Overvoltage Test : 1.5 x VDD or MSV,                   |
|                     |          |                    | PASS -400mA   | -2.75V           | PASS                     | whichever is less                                      |
|                     |          |                    |               |                  |                          | Class I B :  |
| I Trigger (-)       | IO5.5V   | 3                  |               |                  |                          | If immunity level A cannot be achieved                 |
|                     |          | -                  |               |                  |                          | CLASS II   |
|                     |          |                    |               |                  |                          | For Latch-up test at maximum-rate                      |
|                     |          |                    |               |                  |                          | ambient temperature                                    |
|                     |          |                    |               |                  |                          | Class II A :   |
|                     |          | VDD5.5V            |               | +600mA           |                          | Positive I-Test : ≥ 100mA                              |
| Over Volt Test      | VDD5 5V  |                    | PASS +8.25V   |                  |                          | Negative I-Test : ≧ 100mA                              |
| V <sub>supply</sub> | VDD3.3V  |                    | FA33 +0.23V   | TOUUIIA          |                          | Overvoltage Test : 1.5 x VDD or MSV, whichever is less |
|                     |          |                    |               |                  |                          | Class IIB:   |
|                     |          |                    |               |                  |                          | If immunity level A cannot be achieved                 |

VCAP 外接 1.0UF 电容到地

**Group Pins** GND 8,23,47 VCAP1.5V 1

IO5.5V 2-7,10-22,25-46

VDD5.5V 9,24,48

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## 2.2 测试数据 (TEST DATA)

| Tested Pins Team | l Trigger (Positive)<br>Sample No. & Failed current (mA) |               |                            |  |  |
|------------------|--|---------------|----------------------------|--|--|
| 2                | #11  | #12           | #13                        |  |  |
|                  | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 3                | PASS +400mA  | PASS +400mA   | PASS +400MA<br>PASS +400MA |  |  |
| 4                |  |               |                            |  |  |
|                  | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 5                | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 6                | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 7                | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 10               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 11               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 12               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 13               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 14               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 15               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 16               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 17               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 18               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 19               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 20               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 21               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 22               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 25               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 26               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 27               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 28               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 29               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 30               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 31               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 32               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 33               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 34               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 35               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 36               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 37               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 38               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 39               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 40               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 41               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 42               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 43               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 44               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 45               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| 46               | PASS +400mA  | PASS +400mA   | PASS +400mA                |  |  |
| <del>4</del> 0   | FA33 +400IIIA  | FA33 +400IIIA | FA33 +400IIIA              |  |  |



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| Tested Pins Team    | l Trigger (Negative) Sample No. & Failed current (mA) |             |             |  |  |
|---------------------|---|-------------|-------------|--|--|
| resteu Filis Tealii | #11   | #12         | #13         |  |  |
| 2                   | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 3                   | PASS -400MA   | PASS -400MA | PASS -400MA |  |  |
|                     |   |             |             |  |  |
| 4                   | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 5                   | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 6                   | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 7                   | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 10                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 11                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 12                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 13                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 14                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 15                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 16                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 17                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 18                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 19                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 20                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 21                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 22                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 25                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 26                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 27                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 28                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 29                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 30                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 31                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 32                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 33                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 34                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 35                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 36                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 37                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 38                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 39                  | PASS -400MA   | PASS -400MA | PASS -400mA |  |  |
| 40                  | PASS -400MA   | PASS -400MA | PASS -400MA |  |  |
| 41                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 41                  | PASS -400MA   | PASS -400MA | PASS -400MA |  |  |
| 42                  | PASS -400MA   | PASS -400MA | PASS -400MA |  |  |
|                     |   |             |             |  |  |
| 44                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 45                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |
| 46                  | PASS -400mA   | PASS -400mA | PASS -400mA |  |  |

| No                  | Over Voltage Test for V <sub>supply</sub> |                           |             |  |
|---------------------|---|---------------------------|-------------|--|
| Tested Pins Team    | Sample N                                  | No. & Failed current (mA) |             |  |
| resteu Filis Tealii | #11                                       | #12                       | #13         |  |
| 9                   | PASS +8.25V                               | PASS +8.25V               | PASS +8.25V |  |
| 24                  | PASS +8.25V                               | PASS +8.25V               | PASS +8.25V |  |
| 48                  | PASS +8.25V                               | PASS +8.25V               | PASS +8.25V |  |

#### 《以下空白》

#### << The Following Blank >>

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